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Docket No.

252121US2S/ams

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Keiichi KUSHIDA, et al.

SERIAL NO:

10/828,282

GAU:

FILED:

April 21, 2004

**EXAMINER:** 

FOR:

SEMICONDUCTOR DEVICE WITH MEMORY AND METHOD FOR MEMORY TEST

### **INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97**

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

#### REFERENCES

The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed
references are attached, where required, as are either statements of relevancy or any readily available English
translations of pertinent portions of any non-English language references.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

#### **RELATED CASES**

Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present
application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s)
is attached along with PTO 1449.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

#### CERTIFICATION

$\Box$	Each item of information contained in this information disclosure statement was first cited in any communication
	from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of
	this statement.

□ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

#### DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Marvin J. Spivak

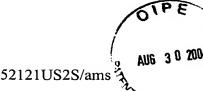
Registration No. 24,913

Joseph A. Scafetta, Jr. Registration No. 26, 803

Customer Number

22850

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 05/03)



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## **STATEMENT OF RELEVANCY**

References AA and AO on Form PTO-1449 are discussed in the specifications.

SHEET OF

AUG 3 0 2004 ATTY DOCKET NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SERIAL NO. Form PTO 1449 (Modified) 252121US2S 10/828,282 WALLEY! **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Keiichi KUSHIDA, et al. FILING DATE **GROUP** April 21, 2004 **U.S. PATENT DOCUMENTS EXAMINER DOCUMENT** SUB FILING DATE DATE NAME **CLASS** NUMBER INITIAL **CLASS** IF APPROPRIATE 6,295,617 09/25/2001 AA S. SONOBE AΒ AC AD ΑE ΑF AG ΑН ΑI ΑJ ΑK ΑL AM ΑN FOREIGN PATENT DOCUMENTS **DOCUMENT TRANSLATION** DATE COUNTRY NUMBER YES NO AO 2001-351398 12/21/2001 **JAPAN** Х AP AQ AR AS AT ΑU ΑV OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) P. RAMANATHAN, et al., IEEE VLSI Test Symposium, pages 292-297, "ZERO COST TESTING OF CHECK BITS IN RAMS ΑW WITH ON-CHIP ECC", April 7-9, 1992 AX AY ΑZ Additional References sheet(s) attached Examiner **Date Considered** \*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.